

# RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1267	Jan-96	9544 A1	ANAM, K.	DN518301AAN	1.2μ OX/NI	16 SOIC

**STRESS/JOB NO.**

**READPOINT**

**(Sample Size/No. of Fails)**

Preconditioning (P/C):  
85°C/85% RH, 168 hours  
HTC Vapor Phase, 3 Passes  
P-16821

<u>Electrical</u>	<u>Cum %</u>
240/0	0.0%

Sonoscan  
P-16822

<u>Post Vapor Phase</u>
8/0

Infant / High Voltage Life  
125°C, -4.0 & +6.0 V  
P-16880, P-16905

<u>48 Hr</u>	<u>336 Hr</u>	<u>1K Hr</u>	<u>*Failure Rate</u>
239/0	77/0	77/0	82 Fits

\*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle  
-55°C to +125°C  
P-16906

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
51/0	51/0	0.0%

Biased Moisture (HAST)  
120°C/85% RH, 5.5 V.  
P-16907

<u>100 Hr</u>	<u>200 Hr</u>	<u>Cum %</u>
66/0	66/0	0.0%

Autoclave  
121°C/100% RH, 2 Atmos  
P-16908

<u>168 Hr</u>	<u>Cum %</u>
45/0	0.0%

**Failure Mode**